Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/792,293	LOEW ET AL.		
Examiner	Art Unit		
Patrick J. Lee	2878		

SEARCHED				
Class	Subclass	Date	Examiner	
250	205, 208.1, 214C	12(12(05)	PL	
327	514	12/14/2005	PL	
313	531	12/14/2005	PL	
315	10	12/14/2005	PL	
315	156-159	12/14/2005	PL	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	12/12/2005	PL		
Consulted w/ S. Allen AU 2878 CL 250	12/13/2005	PL		
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	12/14/2005	PL		